

Low Offset, High PSRR, CMOS Bandgap Voltage Reference

Abstract. A CMOS Bandgap Voltage Reference (BVR) with the characteristics of low offset and high power-supply rejection ratio (PSRR) is presented. In order to reduce the effect of offset of operation amplifier (OPA), the voltage difference of base-emitter junctions of substrate bipolar transistors is maximized; meanwhile the factor of offset voltage could be minimized. The feedback loop constructed by proportional to absolute temperature (PTAT) current source and an OPA is employed to improve the PSRR. The circuit was designed and simulated in a standard 0.35- μm CMOS process, with a power supply of 3 volt. The relative accuracy is increased by 5 times compared with conventional circuit. PSRR of the circuit is $\sim 108\text{dB}$ at low-frequency. Furthermore, temperature coefficient (TC) of $17\text{ppm}/^\circ\text{C}$ over a wide temperature range of $-40 \sim 115^\circ\text{C}$. The whole circuit including the OPA draws only $22 \mu\text{A}$ from supply voltage. Silicon area is 0.037mm^2 .

Streszczenie. Opisano pasmowy wzorec napięcia w technologii CMOS charakteryzujący się małym pełzaniem zera i dużym współczynnikiem usuwania składowej zasilającej. Układ zaprojektowano w technologii $0.35\mu\text{m}$ z napięciem zasilania 3V. (Pasmowy wzorec napięcia z małym pełzaniem zera i dużym współczynnikiem PSRR)

Keywords: Offset, PSRR, CMOS, Bandgap voltage reference, PTAT.

Słowa kluczowe: wzorec napięcia, technologia CMOS

Introduction

Bandgap voltage references are basic functional circuit blocks that provide a temperature and supply insensitive output voltage. High precision voltage references are widely used in many integrated circuit (IC) chips, such as, power management, temperature sensors, dynamic random access memory (DRAM), flash memories, analog-to-digital converters (ADCs), and digital-to-analog converters (DACs).

Bandgap voltage references are required to be stabilized over temperature variations, process, and supply voltage. Traditionally, bandgap voltage reference, with low temperature sensitivity is generally obtained as the sum of a voltage that is proportional to absolute temperature (PTAT) and a voltage with negative temperature coefficient, which is complementary to absolute temperature (CTAT) [1]. The PTAT voltage is the voltage difference of two base-emitter junctions of substrate bipolar transistors. The CTAT voltage is usually obtained from the voltage across a forward biased p-n junction or the base-emitter voltage (V_{BE}) of a diode connected bipolar junction transistor (BJT) as illustrated in Fig.1. The term V_T indicated in this figure is the thermal voltage and equal of kT/q , where k is the Boltzmann constant, T is the Kelvin temperature and q is the electron charge.

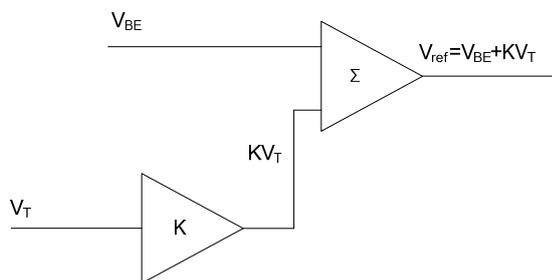


Fig.1. Block diagram of a BVR

In addition to temperature variations, the accuracy of Bandgap voltage is affected by OPA offset. Offset results from the inherent random offset in MOSFETs transistors gate source voltages which arises from the mismatches in threshold voltages, W/L ratios, and electron and hole mobility [2]. Several techniques for low offset could be found in the literatures or books [3, 4]. The supply noise injected to the output of Bandgap reference circuit also

significantly influence the accuracy of Bandgap voltage. Much work on improving PSRR has been done in [5, 6].

In Sect.2-5, the proposed design methodology and circuit implementation are presented. Layout design and simulation results are discussed in Sect.6 and conclusions are explained in Sect.7.

Conventional CMOS Bandgap Voltage Reference

The core of a Conventional BVR circuit is shown in Fig.2. It is assumed that the offset voltage is V_{OS} , according to the feedback principle of the amplifier, the voltages at the nodes X and Y are equal, so the current of I_2 is $(\Delta V_{EB} + V_{OS})/R_1$. The current of I_3 is mirrored from M_2 , hence the output voltage will be:

$$V_{ref} = V_{EB3} + M \cdot \frac{R_2}{R_1} [\Delta V_{EB} + V_{OS}] \quad (1)$$

where M is a constant, V_{EB3} is a CTAT voltage, ΔV_{EB} is $(V_{EB1} - V_{EB2})$ equal to $V_T \ln N$, V_T is a PTAT voltage. By proper choosing the value of M , R_2/R_1 , and N , the Bandgap output voltage with zero temperature coefficients can be achieved in a specified temperature of T_0 .

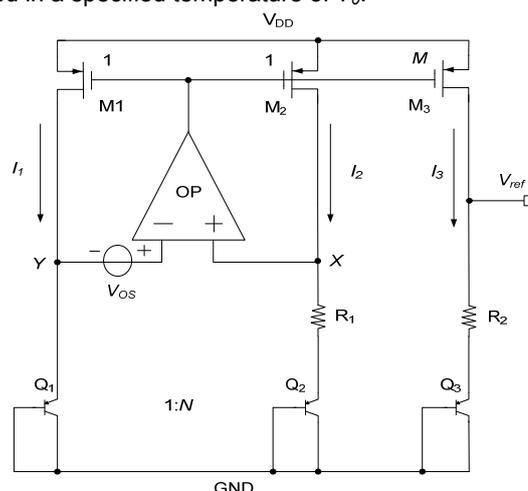


Fig.2. The conventional BVR with offset

However the offset voltage V_{OS} is amplified by a factor $M \cdot R_2/R_1$. As a result the reference voltage precision may be affected, especially in CMOS process [7]. Therefore, the OPA offset voltage is the prevailing source of process induced error in CMOS BVR architecture similar to Fig.2.

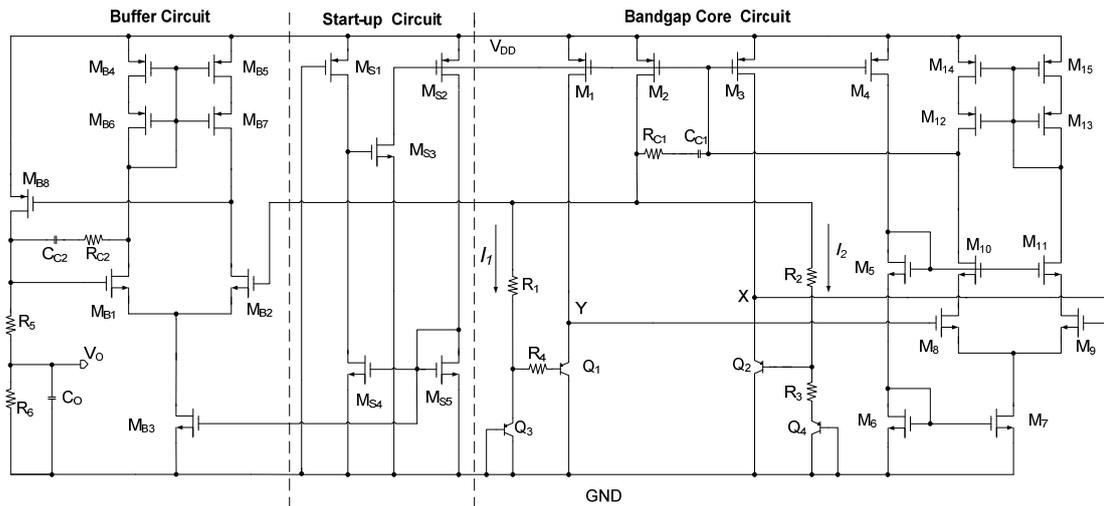


Fig.4. Bandgap Voltage Reference circuit

Layout design and experimental results

Fig.5 shows the microphotograph of the whole Bandgap voltage reference circuit and silicon area is 0.037mm^2 . It is known that mismatches of resistors, current mirror and bipolar transistors may seriously affect its performances [10]. In order to minimize mismatches, a group of parallel resistors with identical geometries are used. Current mirror and bipolar transistors are respectively in symmetrical array.

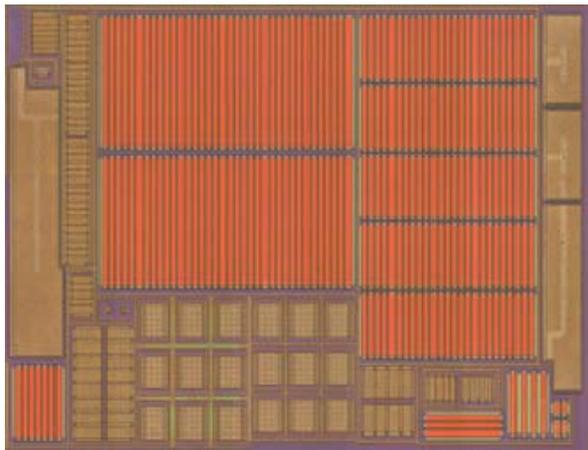


Fig.5. Microphotograph of the BVR

The parasitic parameters of the BVR layout are extracted, and simulation based on standard $0.35\text{-}\mu\text{m}$ CMOS process has been carried out. Fig.6 shows the curve of Bandgap voltage reference versus temperature characteristics over the range from $-40\sim 115^\circ\text{C}$, it can be seen that the peak-to-peak variation is 1.38mV , the temperature coefficient (TC) $17\text{ppm}/^\circ\text{C}$. The PSRR of the BVR versus frequency is shown in Fig.7. The PSRR is -108dB at a low frequency of less than 100Hz . Table.1 summarizes the performances of the BVR.

Table.1 Summary of performances of BVR

Parameter	Supply voltage	Power dissipation	Area	TC	PSRR@DC	PSRR@100K
Value	3V	$66\mu\text{W}$	0.037mm^2	$17\text{ppm}/^\circ\text{C}$	108dB	55dB

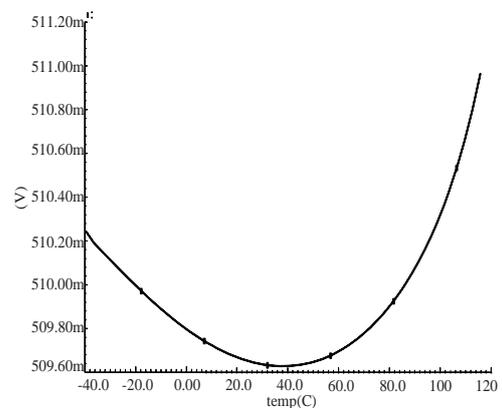


Fig.6. Output reference VO versus temperature

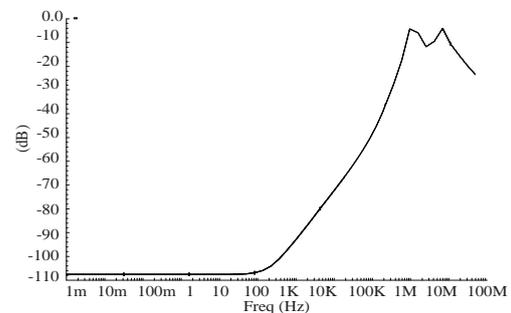


Fig.7. Output reference PSRR versus frequency

In order to observe the effect to restrain offset voltage of improved BVR. Given the stochastic error of current mirror and different pair aroused by arts is $\pm 2\%$. The simulation results of improved circuit and conventional circuit is contrasted in Table.2. The error of output voltage in Conventional circuit is not less than 26.69mV . However, it is only 5.4mV in improved BVR. The relative accuracy is increased by 5 times compared with conventional circuit; the result shows improved circuit significantly restrains the effect of offset voltage.

Table.2 Influence of various mismatches for output voltage

Error item	Conventional circuit		Improved circuit	
	-2%	+2%	-2%	+2%
Current mirror	13.003mV (-1.69%)	+0.533 mV (+0.07%)	+2.5 mV (+0.49%)	-2.8 mV (-0.55%)
Different pair	+0.128 mV (+0.17%)	+13.683 mV (+1.78%)	-2.9 mV (-0.57%)	+2.3 mV (+0.45%)

Conclusion

This paper has presented a low offset and high PSRR Bandgap voltage reference, which generates an output voltage of 510mV. The circuit features PN in series and appropriate layout to achieve low offset, in addition, feedback loop, self-biased OPA and RC low pass filter for high PSRR. Stimulation result shows that the BVR circuit achieved the reported high PSRR of -108dB at low frequency. Furthermore, TC of 17ppm/°C over a wide temperature range of -40~115°C. The whole BVR circuit occupies 0.037mm² silicon areas, and consumes 22μA current. It can be used in many applications such as lighting and ballast ICs [11-14].

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